Special Issue

Fringe Projection Profilometry for Fast and Accurate 3D Surface Analysis

Message from the Guest Editors

The outstanding features of Fringe projection profilometry (FPP) rely on its ability to provide automatic, accurate, high-resolution, full-field 3D surface information. Even if several approaches have been proposed in the last years, 3D surface analysis in real scenarios is still affected by many problems, due to a variety of global illumination effects (high reflectivity, inter-reflections, surface scattering, etc.). FPP is still an active research field for the scientific community.

Keywords

- Fringe projection profilometry
- Phase shifting
- Structured light sensing
- 3D shape measurement
- 3D imaging
- Phase unwrapping
- 3D surface analysis
- Camera calibration
- Optical metrology

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Deadline for manuscript submissions

closed (31 December 2019)

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/si/22159

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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